

**Search Notes****Application/Control No.**

10/620,840

**Examiner**

Shin-Lin Chen

**Applicant(s)/Patent under Reexamination**

DUFF, KAREN

**Art Unit**

1632

**SEARCHED**

Class	Subclass	Date	Examiner
800	13		
800	18		
800	21		
536	23.5		
536	24.1		
435	455	8/14/2006	GN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated, inventor search, parents updated and reviewed.	8/14/2006	GN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
800	18		
800	13		
800	21		
526/23.5, 24.1, 435/455, AU interference search	8/14/2006	GN	